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Applicant: SHENZHEN SANYEAR ELECTRONICS CO.LTD

Address: 11TH FLOOR, NANGUANG BUILDING, HUAFU ROAD, FUTIAN DISTRICT, SHENZHEN

Manufacturer: SHENZHEN SANYEAR ELECTRONICS CO.LTD

Address: 11TH FLOOR, NANGUANG BUILDING, HUAFU ROAD, FUTIAN DISTRICT, SHENZHEN

The following samples were submitted and identified on behalf of the clients as:

Sample name: Chip resistor

Brand: SANYEAR

Model(s): 0201, 0402, 0603, 0805, 1206, 2010, 2512, 3920, 5930

Sample received date: May 21,2024

Testing period: May 21,2024 to May 23,2024

Test Method: Please refer to next page(s). **Test Result:** Please refer to next page(s).

Result Summary:

Test Requested	Conclusion			
European Directive 2011/65/EU and amendment (EU) 2015/863 on the restriction of the use of				
certain hazardous substances in electrical and electronic equipment	PASS			

Tested By:

Check By:

Approve By:

Date: May 23, 2024



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Sample Description:

No.	Description Description
1	Chip resistor

Test Method:

Test Item(s)	Test Method	Analysis Equipment(s)	MDL	Limit
Lead (Pb)	IEC 62321-5:2013	ICP-OES	2 mg/kg	1000mg/kg
Cadmium (Cd)	IEC 62321-5:2013	ICP-OES	2 mg/kg	100mg/kg
Mercury (Hg)	IEC 62321-4:2013+AMD1:2017	ICP-OES	2 mg/kg	1000mg/kg
Hexavalent Chromium Cr(VI)	IEC 62321-7-1:2015	UV-VIS	D TE	1000mg/kg

Test Result(s):

Tack Ham(c)	Limit	Unit	Result 1	
Test Item(s)	As As As	40 40 40		
Lead (Pb)	1000	mg/kg	N.D	
Cadmium (Cd)	100	mg/kg	N.D	
Mercury (Hg)	1000	mg/kg	N.D	
Hexavalent Chromium (Cr(VI)	A A A	mg/kg	Negative	
Conclusion	C' C' C' C		PASS	

Remark:

- -MDL = Method Detection Limit
- -N.D. = Not Detected (<MDL)
- -mg/kg = ppm = parts per million
- -Negative = Absence of Cr(VI), the detected Cr(VI) concentration in the boiling water extraction solution is less than 0.1 mg/kg with 50cm2 sample surface area used.
- -Positive = Presence of Cr(VI), the detected Cr(VI) concentration in the boiling water extraction solution is equal to or greater than 0.13 mg/kg with 50cm2 sample surface area used.

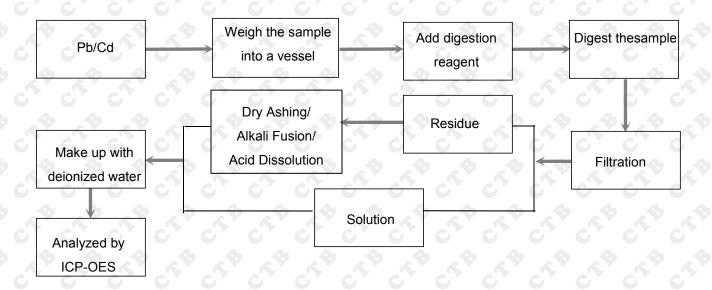


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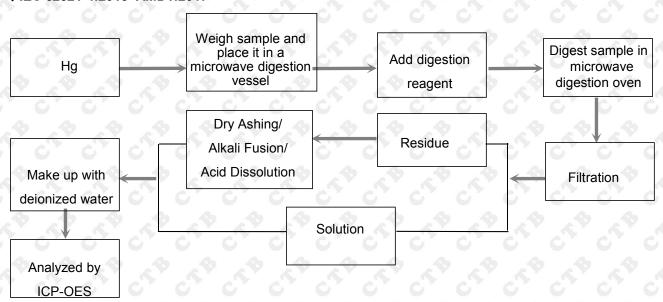
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Test flow chart

♦IEC 62321-5:2013



♦IEC 62321-4:2013+AMD1:2017

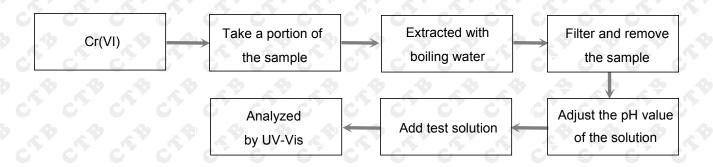




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♦IEC 62321-7-1:2015



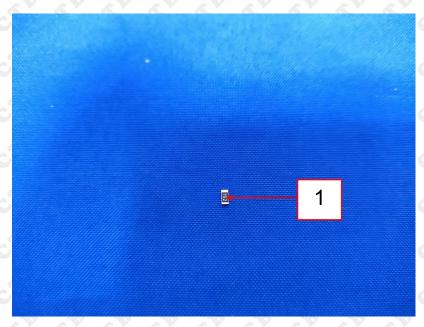


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Photo documentation





*** End of Report ***

Note:If there is any objection to the inspection results in this report, please submit a written report to the company within 15 days from the date of receiving the report. The test report is effective only with both signature and specialized stamp. This result(s) shown in this report refer only to the sample(s) tested. Without written approval of Shenzhen CTB Testing Technology Co., Ltd. this report can't be reproduced except in full. The tested sample(s) and the sample information are provided by the client. "*" indicates the testing items were fulfilled by subcontracted lab. "#" indicates the items are not in CNAS accreditation scope.